TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

# TC74ACT521P, TC74ACT521F, TC74ACT521FW

#### **8-BIT EQUALITY COMPARATOR**

The TC74ACT521 is an advanced high speed CMOS 8-BIT DIGITAL COMPARATOR fabricated with silicon gate and double-layer metal wiring C2MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

This device may be used as a level converter for interfacing TTL or NMOS to High Speed CMOS. The inputs are compatible with TTL, NMOS and CMOS output voltage levels.

It compares two 8-bit binary or BCD words applied inputs  $P_0 \sim P_7$ , and inputs  $Q_0 \sim Q_7$ , and indicates whether or not they are equal.

A signal active low enable is provided to facilitate cascading of several packages to compare of words greater than 8 bits. All inputs are equipped with protection circuits against static discharge or transient excess voltage.

#### FEATURES:

- High Speed····· $t_{pd} = 6.4 \text{ns}(typ.)$  at  $V_{CC} = 5V$
- Low Power Dissipation ············· $I_{CC} = 8\mu A(Max.)$  at Ta = 25°C
- Compatible with TTL outputs  $\cdots$   $V_{IL} = 0.8V$  (Max.)

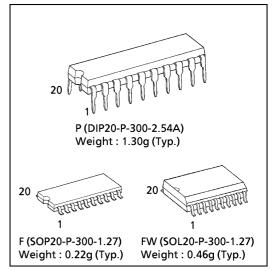
 $V_{IH} = 2.0V (Min.)$ 

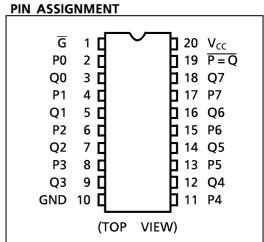
• Symmetrical Output Impedance | | I<sub>OH</sub> | = I<sub>OL</sub> = 24mA(Min.)

Capability of driving  $50\Omega$  transmission lines.

- Balanced Propagation Delays ····· t<sub>pLH</sub> ≃ t<sub>pHL</sub>
- Pin and Function Compatible with 74F521

(Note) The JEDEC SOP (FW) is not available in Japan.





## TRUTH TABLE

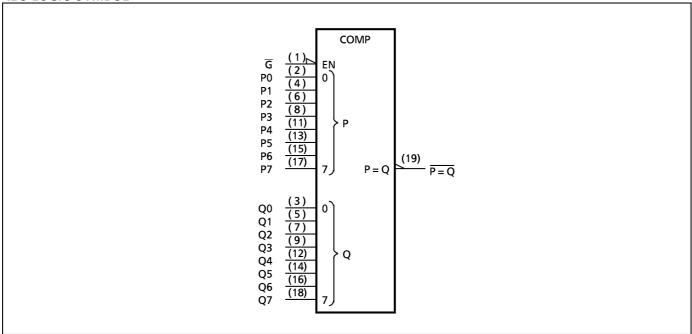
INP	UTS	OUTPUT
P, Q	G	$\overline{P} = \overline{Q}$
P = Q	L	L
P≠ Q	L	Н
Х	Н	Н

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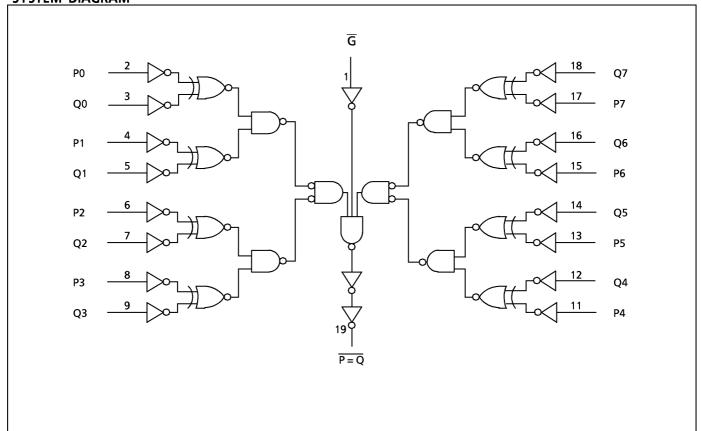
X : Don't Care

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# **IEC LOGIC SYMBOL**



## **SYSTEM DIAGRAM**



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## **ABSOLUTE MAXIMUM RATINGS**

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	V <sub>cc</sub>	-0.5~7.0	V
DC Input Voltage	V <sub>IN</sub>	$-0.5 \sim V_{CC} + 0.5$	V
DC Output Voltage	V <sub>OUT</sub>	−0.5~V <sub>CC</sub> + 0.5	V
Input Diode Current	I <sub>IK</sub>	± 20	mA
Output Diode Current	I <sub>OK</sub>	± 50	mA
DC Output Current	I <sub>OUT</sub>	± 50	mA
DC V <sub>cc</sub> /Ground Current	I <sub>cc</sub>	± 100	mA
Power Dissipation	P <sub>D</sub>	500 (DIP)* / 180 (SOP)	mW
Storage Temperature	$T_{stg}$	<b>−65~150</b>	°C

<sup>\*500</sup>mW in the range of Ta =  $-40^{\circ}\text{C}\sim65^{\circ}\text{C}$ . From Ta =  $65^{\circ}\text{C}$  to  $85^{\circ}\text{C}$  a derating factor of -10mW/°C should be applied up to 300mW.

#### RECOMMENDED OPERATING CONDITIONS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	$V_{CC}$	4.5~5.5	V
Input Voltage	VIN	0~V <sub>cc</sub>	V
Output Voltage	V <sub>OUT</sub>	0~V <sub>cc</sub>	V
Operating Temperature	T <sub>opr</sub>	<b>−40~85</b>	°C
Input Rise and Fall Time	dt/dV	0~10	ns / V

#### DC ELECTRICAL CHARACTERISTICS

De ELECTRICAL CHARACTERISTICS										
PARAMETER SYMB	SYMBOL	TEST CONDITION		V <sub>CC</sub>		Ta = 25°C		Ta = −40~85°C		UNIT
FARAIVIETER STIVIBOL		TEST CONDITION		(V)	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
High - Level Input Voltage	VIH		4.5 \$ 5.5	2.0	ı	_	2.0	_	V	
Low - Level Input Voltage	VIL		4.5 \$ 5.5	_	1	0.8	_	0.8	V	
High - Level Output Voltage	V <sub>OH</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -50 \mu A$ $I_{OH} = -24 m A$ $I_{OH} = -75 m A^*$	4.5 4.5 5.5	4.4 3.94 —	4.5 _ _	_ _ _	4.4 3.80 3.85	_ _ _	٧
Low - Level Output Voltage	V <sub>OL</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 50 \mu A$ $I_{OL} = 24 m A$ $I_{OL} = 75 m A*$	4.5 4.5 5.5		0.0 — —	0.1 0.36 —	_ _ _	0.1 0.44 1.65	٧
Input Leakage Current	I <sub>I N</sub>	$V_{IN} = V_{CC}$ or GND		5.5	_	ı	± 0.1	_	± 1.0	_
	$I_{CC}$ $V_{IN} = V_{CC}$ or GND		5.5			8.0	_	80.0	$\mu$ <b>A</b>	
Quiescent Supply Current $I_C$ PER INPUT : $V_{IN} = 3.4V$ OTHER INPUT : $V_{CC}$ or GN		$V_{CC} = 3.4V$ : $V_{CC}$ or GND	5.5	_	_	1.35	_	1.5	mA	

<sup>\* :</sup> This spec indicates the capability of driving  $50\Omega$  transmission lines. One output should be tested at a time for a 10ms maximum duration.

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## AC ELECTRICAL CHARACTERISTICS ( $C_L$ = $50pF,\,R_L$ = $500\,\Omega,\,lnput\,\,t_r$ = $t_f$ = 3ns )

PARAMETER	SYMBOL	TEST CONDITION		Ta = 25°C			Ta = −40~85°C		UNIT
	STIVIBUL		V <sub>cc</sub> (V)	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
Propagation Delay Time (Pn, Qn – $\overline{P} = \overline{Q}$ )	t <sub>pLH</sub> t <sub>pHL</sub>		5.0 ± 0.5	1	7.1	11.4	1.0	13.0	ns
Propagation Delay Time $(\overline{G} - \overline{P} = \overline{Q})$	t <sub>pLH</sub> t <sub>pHL</sub>		5.0 ± 0.5	ı	5.7	8.3	1.0	9.5	113
Input Capacitance	C <sub>IN</sub>			_	5	10	_	10	٦
Power Dissipation Capacitance	C <sub>PD</sub> (1)			_	29	_	_	_	pF

Note (1)  $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

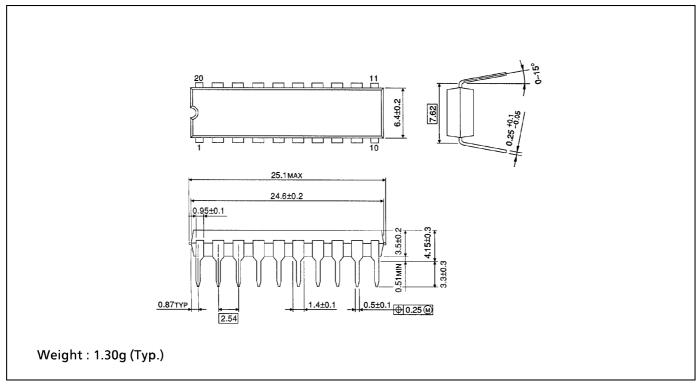
Average operating current can be obtained by the equation:

$$I_{CC}(opr.) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

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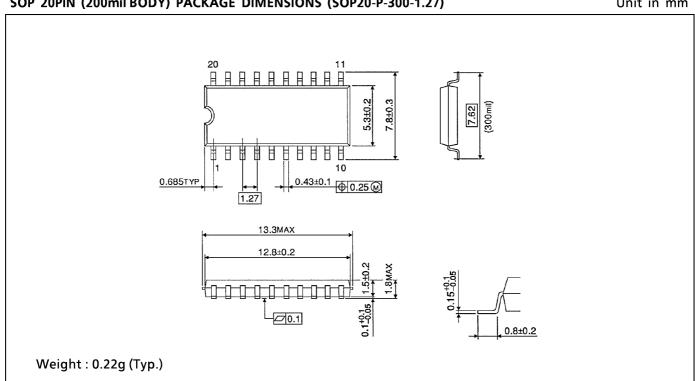
## DIP 20PIN PACKAGE DIMENSIONS (DIP20-P-300-2.54A)

Unit in mm



## SOP 20PIN (200mil BODY) PACKAGE DIMENSIONS (SOP20-P-300-1.27)

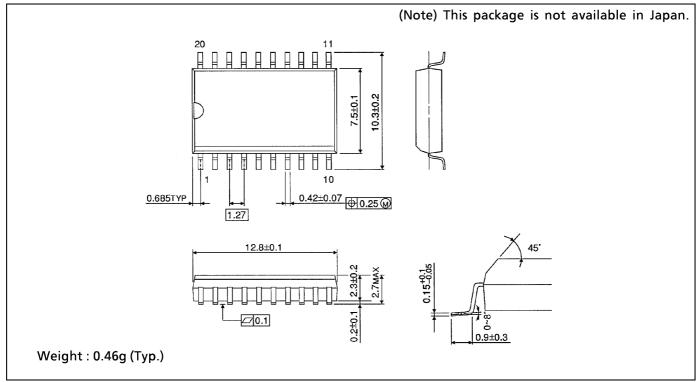
Unit in mm



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# SOP 20PIN (300mil BODY) PACKAGE DIMENSIONS (SOL20-P-300-1.27)

Unit in mm



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